REMARKS

As a preliminary matter, Applicants once again note that an acknowledgment of the receipt and consideration of the Information Disclosure Statement (IDS) filed on July 27, 2000 has not been received. As an indication of consideration of the references cited in the IDS, Applicants respectfully request an initialed copy of the Form PTO-1449 that accompanied the IDS. For the Examiner's convenience, Applicants have enclosed an additional copy of that Form PTO-1449.

The drawings stand objected to under 37 C.F.R. 1.83(a) for allegedly not showing all of the claimed features. Applicants respectfully traverse this objection.

Applicants respectfully submit that all of the features of the claims are shown in the figures. In particular, all of the features of Claim 7 are shown in Figure 8. More specifically, Figure 8 shows a first electrically isolated line 227 and a second electrically isolated line 221. Accordingly, as it has been shown that all of the features of Claim 7 are shown in Figure 8, Applicants respectfully request the withdrawal of this objection to the drawings.

Claims 3, 6 and 7 stand rejected under 35 U.S.C. § 102 (b) as being anticipated by United States Patent No. 5,995,178 to Fujikawa et al. Applicants respectfully traverse this rejection.

Initially, Applicants respectfully submit that the Fujikawa et al. reference does not qualify as a §102(b) prior art reference because its publication date is not more than one year earlier than the filing date of the present application. However, because the Fujikawa et

al. reference may qualify as prior art under another portion of §102, such as §102(e), Applicants will respond to this rejection as though a §102(e) rejection had been made.

Applicants respectfully submit that all of the claimed features of the present invention are not disclosed in the cited reference. In particular, the Fujikawa et al. reference fails to disclose a method for repairing a defect in a display that includes, *inter alia*, a step of forming a bypass for a broken portion of a gate bus line by separating or connecting the gate bus line from or to "at least two of the following: a drain electrode, a source electrode of a TFT, a pixel electrode, and a storage capacitor bus line" (emphasis added), as defined in independent Claim 3. Nor does the Fujikawa et al. reference disclose a repair method that includes, *inter alia*, "forming an alternate conductive path through a pixel electrode and a source electrode," as defined in independent Claim 6.

First, with regard to Claim 3, the repair method of this claim is defined as including a bypass that includes at least two of the following: a drain electrode, a source electrode, a pixel electrode and a storage capacitor bus line. In contrast, Figures 1, 2A and 2B of the Fujikawa et al. reference show a bypass for broken portion 28 of gate line 15 that only passes through pixel electrode 12, without passing through a second component chosen from the following -- a drain electrode, a source electrode of a TFT, and storage capacitor bus line. Similarly, Figures 3, 4A, and 4B of the Fujikawa et al. reference show a similar bypass, but this bypass also includes metal conductive layer 41. However, this bypass also fails to include a second component chosen from the following -- a drain electrode, a source electrode of a TFT, and a storage capacitor bus line. Additionally, none of the other

embodiments of the Fujikawa et al. reference disclose the bypass as defined in independent Claim 3. Accordingly, as all of the features of independent Claim 3 are not disclosed in the Fujikawa et al. reference, Applicants respectfully request that this §102(e) rejection of this claim be withdrawn.

Second, with regard to Claim 6, the repair method of this claim is defined as including a bypass for a broken portion of a gate bus line created by forming an alternate conductive path through a pixel electrode and a source electrode. In contrast, the bypass for the gate bus line 15 of the Fujikawa et al. reference of Figures 1 and 2 only includes the pixel electrode 12, and does not include the source electrode. A similar bypass is shown in Figures 3 and 4 of Fujikawa et al, which bypass also adds metal conductive layer 41, but also fails to include a source electrode. Accordingly, as all of the features of Claim 6 are not disclosed in the Fujikawa et al. reference, Applicants respectfully request the withdrawal of this §102(e) rejection of Claim 6.

Claim 7 depends from independent Claim 6, and therefore includes all of the features of Claim 6, plus additional features. Accordingly, Applicants respectfully request that the §102(e) rejection of dependent Claim 7 under Fujikawa et al. be withdrawn considering the above remarks directed to independent Claim 6.

In addition, Applicants also separately traverse the §102(e) rejection of dependent Claim 7. Applicants respectfully submit that dependent Claim 7, which includes associated independent Claim 6, is directed to forming "a bypass for a broken portion of a gate bus line," where "said bypass [consists] of a conductive path that includes a first edge of

said broken gate bus line, said source electrode, said pixel being sacrificed, said first electrically isolated line, said second electrically isolated line, and a second edge of said broken gate bus line." One example of such a bypass is shown in Figure 8, which includes a first edge of the broken gate bus line (near break 292 of line 218a), a source electrode (228a), a pixel (224a) being sacrificed, a first electrically isolated line (227), a second electrically isolated line (221), and a second edge of the broken gate bus line (near break 292 of line 218a).

In contrast, in Figures 3 and 4 of the Fujikawa et al. reference, the bypass for gate bus line 15 only includes pixel 12 and conductive path 41. Thus, this embodiment of the Fujikawa et al. reference lacks a bypass for a broken portion of a gate bus line that includes a source electrode, a first electrically isolated line, and a second electrically isolated line, as defined in Claim 7.

In the Office Action, the Examiner equated element 42 of the Fujikawa et al. with the claimed first electrically isolated line and element 41 with the claimed second electrically isolated line. However, Applicants respectfully disagree with the Examiner's assertions. Initially, element 41 is attached to scanning (gate) bus line 15, and not to the signal (drain) bus line 17. Thus, element 41 cannot be considered as the "second electrically isolated line on a portion of the drain bus line," as defined in Claim 7

In addition, element 42 of the Fujikawa et al. reference is not used in forming a "bypass for a broken portion of a gate bus line," and therefore element 42 cannot be considered as the claimed "first electrically isolated line." Instead, element 42 is used for a

bypass of a broken portion of a different line -- Cs signal line 16. Thus, element 42 does not contribute to the claimed "bypass for a broken portion of a gate bus line" (Claim 6), where "said bypass [consists] of a conductive path that includes . . . a first electrically isolated line" (Claim 7).

Accordingly, as all of the features of Claim 7 are not disclosed in the Fujikawa et al. reference, Applicants respectfully request the withdrawal of this §102(e) rejection.

For all of the above reasons, Applicants request reconsideration and allowance of the claimed invention. Should the Examiner be of the opinion that a telephone conference would aid in the prosecution of the application, or that outstanding issues exist, the Examiner is invited to contact the undersigned.

Respectfully submitted,

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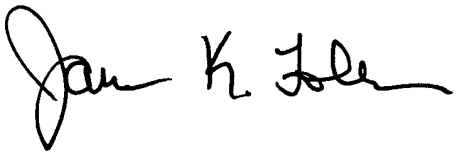
By 

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U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation Yes	Translation No
		54329783	Mar. 10, 1979	Japan			Abs.	
		4234534	Jan. 27, 1992	Japan			Abs.	
		53337373	Dec. 17, 1993	Japan			Abs.	
		63764242	Dec. 6, 1994	Japan			Abs.	
		91139309	May 2, 1997	Japan			Abs.	
		93253536	Dec. 16, 1997	Japan			Abs.	
		11384488	Feb. 12, 1999	Japan			Abs.	
	1	11634799	Jun. 18, 1999	Japan			Abs.	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner	Date Considered

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.